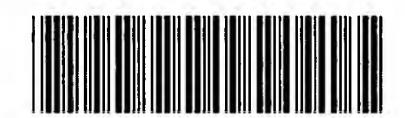
Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination	
10709026	HSIAO, YUAN-KUN	
Examiner	Art Unit	
Singh, Hirdepal	2611	

SEARCHED					
Class	Subclass	Date	Examiner		
375	326, 362, 371, 373, 375-376	9/10/2007	HS		
327	113	9/10/2007	HS		
455	130, 214	9/10/2007	HS		
375	315,326, 362, 371, 373, 375-376	11/20/2007	HS		
369	44.13, 44.26, 44.28, 47, 275.4	11/20/2007	HS		
327	3,5,7,12	11/20/2007	HS		
455	130,214	11/20/2007	HS		

SEARCH NOTES				
Search Notes	Date	Examiner		
US-PG PUB; USPAT; USOCR; FPRS; EPO; JPO; IBM-TDB; DERWENT	9/10/2007	HS		
US-PG PUB; USPAT; USOCR; FPRS; EPO; JPO; IBM-TDB; DERWENT	11/20/2007	HS		
Google Search	11/20/2007	HS		
IEEE Search	11/20/2007	HS		
Plus search	11/20/2007	HS		

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		
375	315	11/20/2007	HS		
375	326	11/20/2007	HS		
375	362	11/20/2007	HS		
375	371	11/20/2007	HS		
375	375	11/20/2007	HS		
375	376	11/20/2007	HS		
327	3	11/20/2007	HS		
327	5	11/20/2007	HS		
327	7	11/20/2007			

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